

MOSFET - Power, N-Channel, Shielded Gate 80 V, 8.3 mΩ, 61 A

NTTFS8D1N08H

General Description

This N-Channel MOSFET is produced using **onsemi**'s advanced MOSFET process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

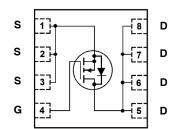
Features

- Shielded Gate MOSFET Technology
- Max $R_{DS(on)} = 8.3 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 16 \text{ A}$
- Max $R_{DS(on)} = 12.6 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 13 \text{ A}$
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

Applications

- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive

ELECTRICAL CONNECTION



N-Channel MOSFET



MARKING DIAGRAM



 1N08
 = Device Code

 A
 = Assembly Location

 Y
 = Year Code

 WW
 = Work Week Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NTTFS8D1N08H	WDFN8 (Pb-Free)	1500 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

MOSFET MAXIMUM RATINGS ($T_A = 25$ °C unless otherwise noted)

Symbol	Parameter				Ratings	Unit
V _{DS}	Drain to Source	Voltage			80	V
V _{GS}	Gate to Source \	/oltage			±20	V
I _D	Drain Current	-Continuous	T _C = 25°C	(Note 5)	61	Α
		-Continuous	T _C = 100°C	(Note 5)	39	
		-Continuous	T _A = 25°C	(Note 1a)	14	1
		-Pulsed		(Note 4)	216	1
E _{AS}	Single Pulse Ava	lanche Energy		(Note 3)	113	mJ
P _D	Power Dissipatio	n	T _C = 25°C		63	W
	Power Dissipation	n	$T_A = 25^{\circ}C$	(Note 1a)	3.2	1
T _J , T _{STG}	Operating and St	orage Junction Temper	rature Range		-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	2	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	39	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units	
OFF CHARACTERISTICS							
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A}, V_{GS} = 0 \text{V}$	80	=	-	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25°C	-	52	-	mV/°C	
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 64 V, V _{GS} = 0 V	-	-	10	μΑ	
I _{GSS}	Gate to Source Leakage Current	V _{GS} = +20 V, V _{DS} = 0 V	-	-	100	nA	
ON CHARACT	ERISTICS						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 80 \mu A$	2.0	2.8	4.0	V	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I _D = 80 μA, referenced to 25°C	-	-7.2	-	mV/°C	
R _{DS(on)}	Static Drain to Source On Resis-	V _{GS} = 10 V, I _D = 16 A	-	6.4	8.3	mΩ	
	tance	V _{GS} = 6 V, I _D = 13 A	-	9	12.6		
DYNAMIC CHA	ARACTERISTICS						
C _{ISS}	Input Capacitance	V _{DS} = 20 V, V _{GS} = 0 V,	-	1450	_	pF	
C _{OSS}	Output Capacitance	f = 1 MHz	-	776	_		
C _{RSS}	Reverse Transfer Capacitance]	-	46	_		
R _G	Gate Resistance		-	0.6	-	Ω	
SWITCHING C	HARACTERISTICS						
t _{d(ON)}	Turn – On Delay Time	V _{DD} = 40 V, I _D = 16 A,	-	9.1	_	ns	
t _{rd(ON)}	Rise Time	V_{GS} = 10 V, R_{GEN} = 2.5 Ω	-	13	-	1	
t _{d(OFF)}	Turn – Off Delay Time]	-	23.8	-	1	
t _f	Fall Time	1 [-	2.5	-	7	

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
WITCHING O	CHARACTERISTICS	_					•
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V		_	23	-	nC
Qg	Total Gate Charge	V _{GS} = 0 V to 6 V		_	9	-	
Q _{gs}	Gate to Source Charge		V _{DD} = 40 V	_	7.2	-	
Q_{gd}	Gate to Drain "Miller" Charge		I _D = 16 A	_	4.2	-	1
RAIN-SOUF	ICE DIODE CHARACTERISTICS						-
V _{SD} Source to Drain Diode Forward	V _{GS} = 0 V, I _S = 16 A	A (Note 2)	-	0.81	1.2	V	
	Voltage	Vcc = 0 V lc = 16 A	(Note 2)	_	0.64	1.3	

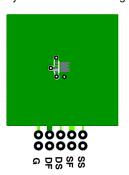
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

 $I_F = 16 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$

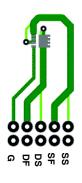
 t_{rr}

 Q_{rr}

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 53°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

40.5

46.8

ns

nC

Reverse Recovery Time

Reverse Recovery Charge

- Pulse Test: Pulse Width < 300 µs, Duty cycle < 2.0%.
 E_{AS} of TBD mJ is based on starting T_J = 25°C; L = 1 mH, I_{AS} = 15 A, V_{DD} = 64 V, V_{GS} = 10 V. 100% test at L = 1 mH, I_{AS} = 15 A.
 Pulsed I_D please refer to SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

TYPICAL CHARACTERISTICS

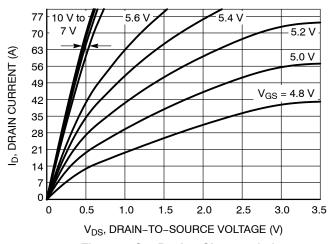


Figure 1. On-Region Characteristics

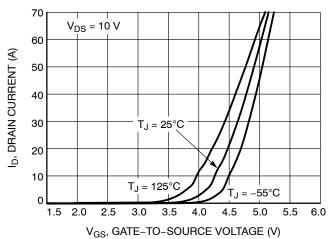


Figure 2. Transfer Characteristics

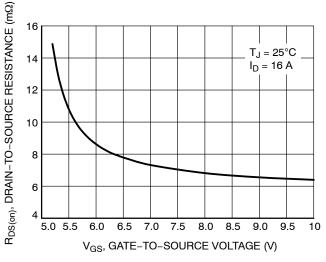


Figure 3. On-Resistance vs. Gate-to-Source Voltage

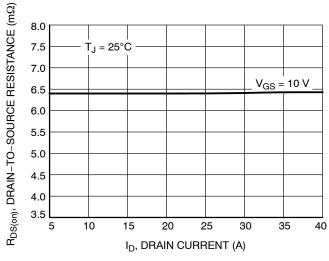


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

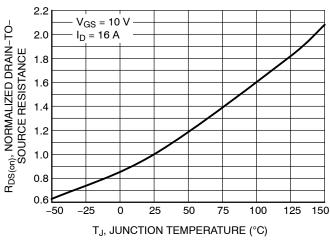


Figure 5. On–Resistance Variation with Temperature

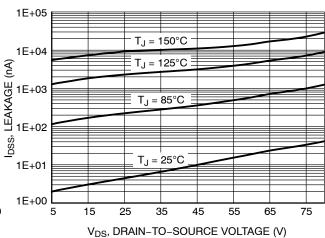


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

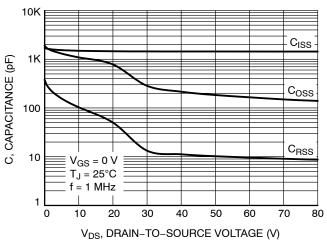


Figure 7. Capacitance Variation

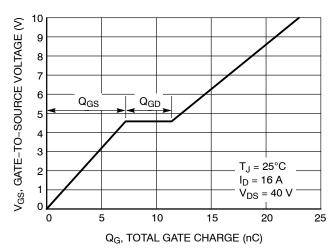


Figure 8. Gate-to-Source Voltage vs. Total Charge

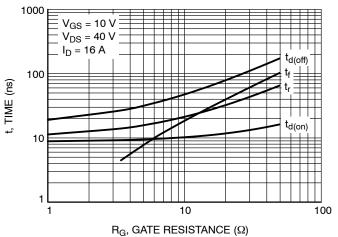


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

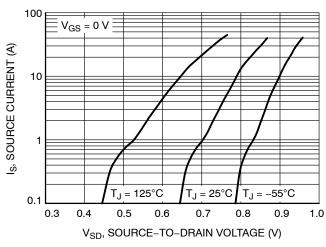


Figure 10. Diode Forward Voltage vs. Current

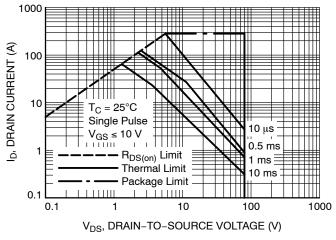


Figure 11. Maximum Rated Forward Biased Safe Operating Area

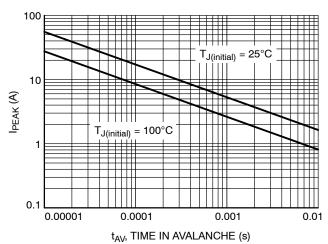


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

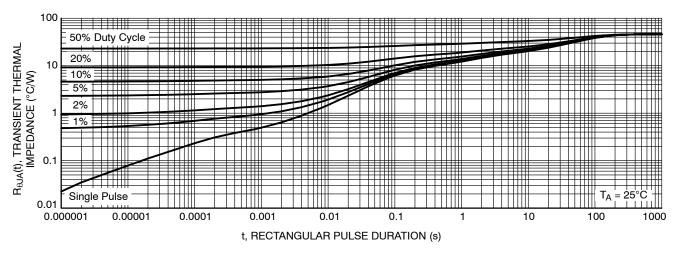


Figure 13. Thermal Response

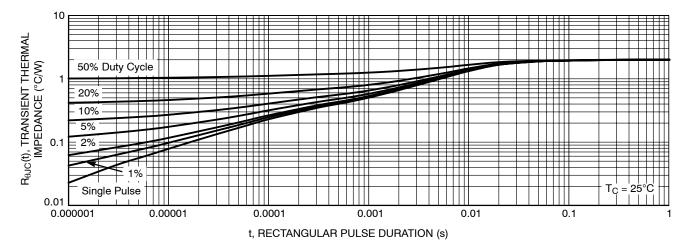
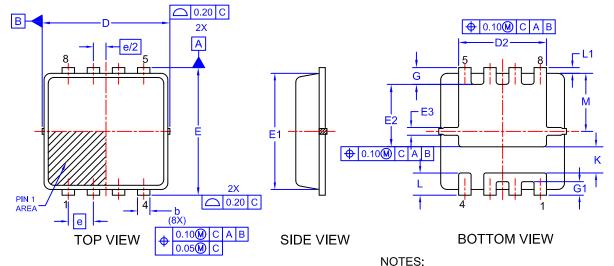


Figure 14. Thermal Response

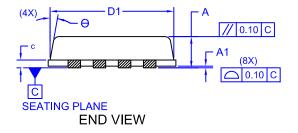


WDFN8 3.3x3.3, 0.65P CASE 511DY ISSUE A

DATE 21 AUG 2018



- 1. CONTROLLING DIMENSION: MILLIMETERS
- 2. DIMENSIONS D1 & E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS NOR GATE BURRS.



	3.	46	-
<u> </u>	8 2.3	88 — 5	
0.78 (4X)			
1 1 1 1 1 1 1 1 1 1			2.51
			4.10
0.57			
0.60 (3.	x) 1		.00 0.43 (8X)

RECOMMENDED LAND PATTERN

GENERIC MARKING DIAGRAM*

XXXX **AYWW**

XXXX = Specific Device Code = Assembly Location = Year Code WW = Work Week Code

DIM	MILLIMETERS			
ווועו	MIN	NOM	MAX	
Α	0.70	0.75	0.80	
A1	0.00	ı	0.05	
b	0.23	0.33	0.43	
С	0.15	0.20	0.25	
О	3.20	3.30	3.40	
D1	2.95	3.13	3.30	
D2	1.98	2.20	2.40	
Е	3.20	3.30	3.40	
E1	2.80	3.00	3.15	
E2	1.40	1.60	1.80	
E3	0.15	0.25	0.40	
е	0.65 BSC			
G	0.30	0.43	0.55	
G1	0.25	0.35	0.45	
K	0.55	0.75	0.95	
L	0.35	0.52	0.65	
L1	0.06	0.15	0.30	
М	1.35	1.50	1.60	
Φ	0	-	12	

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON90827G	Electronic versions are uncontrolled except when accessed directly from the Document Reposit Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	WDFN8 3.3x3.3, 0.65P		PAGE 1 OF 1	

onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. **onsemi** does not convey any license under its patent rights nor the rights of others.

onsemi, Onsemi, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales